

Search Notes

Application/Control No.

10/539,744

Examiner

David E. Bochna

Applicant(s)/Patent under
Reexamination

TOSHIMA ET AL.

Art Unit

3679

SEARCHED

Class	Subclass	Date	Examiner
285	231	10/28/2006	DB
	224		
	232		
	321		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR